# Advance Information

# Low-Voltage CMOS 16-Bit Latching Transceiver With 5V-Tolerant Inputs and Outputs (3-State, Non-Inverting)

The MC74LCX16543 is a high performance, non–inverting 16–bit latching transceiver operating from a 2.7 to 3.6V supply. The device is byte controlled. Each byte has separate control inputs which can be tied together for full 16–bit operation. High impedance TTL compatible inputs significantly reduce current loading to input drivers while TTL compatible outputs offer improved switching noise performance. A V<sub>I</sub> specification of 5.5V allows MC74LCX16543 inputs to be safely driven from 5V devices. The MC74LCX16543 is suitable for memory address driving and all TTL level bus oriented transceiver applications.

For data flow from A to B with the EAB LOW, the A-to-B Output Enable (OEAB) must be LOW in order to enable data to the B bus, as indicated in the Function Table. With EAB LOW, a LOW signal on the A-to-B Latch Enable (LEAB) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the LEAB signal will latch the A latches. and the outputs no longer change with the A inputs. With EAB and OEAB both LOW, the 3-State B output buffers are active and reflect the data present at the output of the A latches. Control of data flow from B to A is symetric to that above, but uses the EBA, LEBA, and OEBA inputs.

- Designed for 2.7 to 3.6V VCC Operation
- 5.2ns Maximum tpd
- 5V Tolerant Interface Capability With 5V TTL Logic
- · Supports Live Insertion and Withdrawal
- IOFF Specification Guarantees High Impedance When VCC = 0V
- LVTTL Compatible
- LVCMOS Compatible
- 24mA Balanced Output Sink and Source Capability
- Near Zero Static Supply Current in All Three Logic States (20μA) Substantially Reduces System Power Requirements
- Latchup Performance Exceeds 500mA
- ESD Performance: Human Body Model >2000V; Machine Model >200V

## MC74LCX16543



LOW-VOLTAGE CMOS 16-BIT LATCHING TRANSCEIVER



**DT SUFFIX**PLASTIC TSSOP PACKAGE
CASE 1202–01

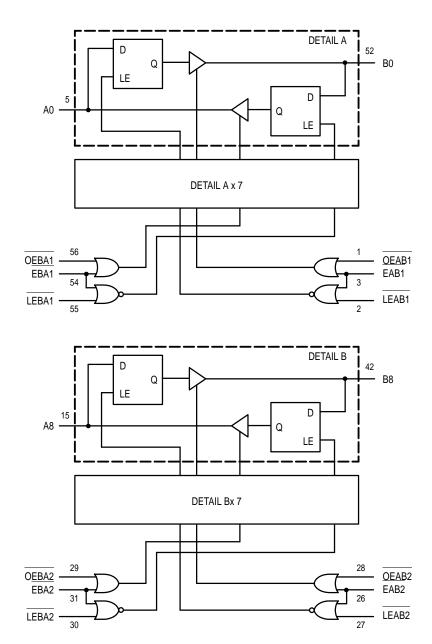
### **PIN NAMES**

1 III IIAIILO	
Pins	Function
OExxn Exxn LExxn A0-A15 B0-B15	Output Enable Inputs Enable Inputs Latch Enable Inputs 3-State Inputs/Outputs 3-State Inputs/Outputs

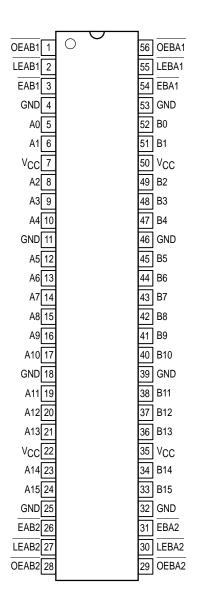
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### **LOGIC DIAGRAM**



Pinout: 56-Lead TSSOP (Top View)



#### **FUNCTION TABLE**

		Inpu	uts			Data Ports		On continue Mode
OEABn	OEBAn	EABn	EBAn	LEABn	LEBAn	An	Bn	- Operating Mode
Н	Н					Input	Input	
		Х	Х	Х	Х	Х	Х	Disable Outputs
		L	L	L	L	X	Х	Transparent Data; Outputs Disabled
				Н	Н	l h	l h	Latch and Outputs Disabled
L	Н					Input	Output	
		Н	X*	L	Х	l h	Z Z	Load and B Outputs Disabled
				Н	Х	Х	Z	Hold; B Outputs Disabled
		L	X*	L	Х	L H	L H	Transparent A to B
				Н	Х	l h	L H	Latch and Display B Outputs
Н	L					Output	Input	
		X*	Н	Х	L	Z Z	l h	Load and A Outputs Disabled
				Х	Н	Z	Х	Hold; A Outputs DIsabled
		X*	L	Х	L	L H	L H	Transparent B to A
				Х	Н	L H	l h	Latch and Display A Outputs

H = High Voltage Level; h = High Voltage Level One Setup Time Prior to the Latch Enable or Enable Low—to—High Transition; L = Low Voltage Level; l = Low Voltage Level One Setup Time Prior to the Latch Enable or Enable Low—to—High Transition; X = Don't Care; \* = The latches are not internally gated with the Output Enables. Therefore, data at the A or B ports may enter the latches at any time, provided that the LExx and Exx pins are set accordingly. For I<sub>CC</sub> reasons, Do Not Float Inputs.

#### **ABSOLUTE MAXIMUM RATINGS\***

Symbol	Parameter	Value	Condition	Unit
Vcc	DC Supply Voltage	-0.5 to +7.0		V
VI	DC Input Voltage	$-0.5 \le V_1 \le +7.0$		V
VO	DC Output Voltage	$-0.5 \le V_{O} \le +7.0$	Output in 3–State	V
		$-0.5 \le V_{O} \le V_{CC} + 0.5$	Note 1.	V
Ιικ	DC Input Diode Current	<b>–</b> 50	V <sub>I</sub> < GND	mA
loк	DC Output Diode Current	-50	V <sub>O</sub> < GND	mA
		+50	AO > ACC	mA
lo	DC Output Source/Sink Current	±50		mA
Icc	DC Supply Current Per Supply Pin	±100		mA
<sup>I</sup> GND	DC Ground Current Per Ground Pin	±100		mA
TSTG	Storage Temperature Range	-65 to +150		°C

<sup>\*</sup> Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute—maximum—rated conditions is not implied.

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<sup>1.</sup> Output in HIGH or LOW State. IO absolute maximum rating must be observed.

### RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Тур	Max	Unit
Vcc	Supply Voltage Operating Data Retention Only	2.0 1.5	3.3 3.3	3.6 3.6	V
VI	Input Voltage	0		5.5	V
VO	Output Voltage (HIGH or LOW State) (3–State)	0 0		V <sub>CC</sub> 5.5	V
IOH	HIGH Level Output Current, V <sub>CC</sub> = 3.0V – 3.6V			-24	mA
loL	LOW Level Output Current, V <sub>CC</sub> = 3.0V – 3.6V			24	mA
loн	HIGH Level Output Current, V <sub>CC</sub> = 2.7V - 3.0V			-12	mA
lOL	LOW Level Output Current, V <sub>CC</sub> = 2.7V – 3.0V			12	mA
TA	Operating Free-Air Temperature	-40		+85	°C
Δt/ΔV	Input Transition Rise or Fall Rate, $V_{IN}$ from 0.8V to 2.0V, $V_{CC}$ = 3.0V	0		10	ns/V

### DC ELECTRICAL CHARACTERISTICS

			$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$		
Symbol	Characteristic	Condition	Min	Max	Unit
V <sub>IH</sub>	HIGH Level Input Voltage (Note 2.)	2.7V ≤ V <sub>CC</sub> ≤ 3.6V	2.0		V
V <sub>IL</sub>	LOW Level Input Voltage (Note 2.)	2.7V ≤ V <sub>CC</sub> ≤ 3.6V		0.8	V
Vон	HIGH Level Output Voltage	$2.7V \le V_{CC} \le 3.6V; I_{OH} = -100\mu A$	V <sub>CC</sub> - 0.2		V
		V <sub>CC</sub> = 2.7V; I <sub>OH</sub> = -12mA	2.2		1
		V <sub>CC</sub> = 3.0V; I <sub>OH</sub> = -18mA	2.4		1
		V <sub>CC</sub> = 3.0V; I <sub>OH</sub> = -24mA	2.2		1
VOL	LOW Level Output Voltage	$2.7V \le V_{CC} \le 3.6V$ ; $I_{OL} = 100\mu A$		0.2	V
		V <sub>CC</sub> = 2.7V; I <sub>OL</sub> = 12mA		0.4	1
		V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 16mA		0.4	1
		V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 24mA		0.55	1
lį	Input Leakage Current	2.7V ≤ V <sub>CC</sub> ≤ 3.6V; 0V ≤ V <sub>I</sub> ≤ 5.5V		±5.0	μΑ
loz	3–State Output Current	$2.7 \le V_{CC} \le 3.6V$ ; $0V \le V_{O} \le 5.5V$ ; $V_{I} = V_{IH}$ or $V_{IL}$		±5.0	μΑ
loff	Power-Off Leakage Current	$V_{CC} = 0V$ ; $V_I$ or $V_O = 5.5V$		10	μΑ
ICC	Quiescent Supply Current	$2.7 \le V_{CC} \le 3.6V$ ; $V_I = GND \text{ or } V_{CC}$		20	μΑ
		$2.7 \le V_{CC} \le 3.6V$ ; $3.6 \le V_I$ or $V_O \le 5.5V$		±20	μΑ
ΔlCC	Increase in I <sub>CC</sub> per Input	2.7 ≤ V <sub>CC</sub> ≤ 3.6V; V <sub>IH</sub> = V <sub>CC</sub> − 0.6V		500	μΑ

<sup>2.</sup> These values of V<sub>I</sub> are used to test DC electrical characteristics only.

### **AC CHARACTERISTICS** (Note 3.; $t_R = t_F = 2.5 \text{ns}$ ; $C_L = 50 \text{pF}$ ; $R_L = 500 \Omega$ )

				Lin	nits		
			$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$				1
			V <sub>CC</sub> = 3.	0V to 3.6V	V <sub>CC</sub> =	= 2.7V	1
Symbol	Parameter	Waveform	Min	Max	Min	Max	Unit
<sup>t</sup> PLH <sup>t</sup> PHL	Propagation Delay An to Bn or Bn to An	1	1.5 1.5	5.2 5.2	1.5 1.5	6.0 6.0	ns
<sup>t</sup> PLH <sup>t</sup> PHL	<u>Propag</u> ation Del <u>ay</u> LEBAn to An or LEABn to Bn	4	1.5 1.5	6.5 6.5	1.5 1.5	7.5 7.5	ns
<sup>t</sup> PZH <sup>t</sup> PZL	Output Enable Time OEBAn to An or OEABn to Bn	2	1.5 1.5	6.5 6.5	1.5 1.5	7.0 7.0	ns
<sup>t</sup> PHZ <sup>t</sup> PLZ	Output Disable Time OEBAn to An or OEABn to Bn	2	1.5 1.5	6.5 6.5	1.5 1.5	7.0 7.0	ns
<sup>t</sup> PZH <sup>t</sup> PZL	Output Enable <u>Time</u> EBAn to An or EABn to Bn	2	1.5 1.5	6.5 6.5	1.5 1.5	7.0 7.0	ns
<sup>t</sup> PHZ <sup>t</sup> PLZ	Output Disable <u>Time</u> EBAn to An or EABn to Bn	2	1.5 1.5	6.5 6.5	1.5 1.5	7.0 7.0	ns
t <sub>S</sub>	Setup Time, HIGH to LOW Data to LExxn	4	2.5		2.5		ns
th	Hold Time, HIGH to LOW Data to LExxn	4	1.5		1.5		ns
t <sub>S</sub>	Setup Time, HIGH to LOW Data to Exxn	4	2.5		2.5		ns
t <sub>h</sub>	Hold Time, HIGH to LOW Data to Exxn	4	1.5		1.5		ns
t <sub>W</sub>	Latch Enable or Enable Pulse Width, LOW	4	3.0		3.0		ns
<sup>t</sup> OSHL <sup>t</sup> OSLH	Output–to–Output Skew (Note 4.)			1.0 1.0			ns

<sup>3.</sup> These AC parameters are preliminary and may be modified prior to release. The maximum AC limits are design targets. Actual performance will be specified upon completion of characterization.

### **DYNAMIC SWITCHING CHARACTERISTICS**

			T <sub>A</sub> = +25°C			
Symbol	Characteristic	Condition	Min	Тур	Max	Unit
V <sub>OLP</sub>	Dynamic LOW Peak Voltage (Note 5.)	$V_{CC} = 3.3V$ , $C_L = 50pF$ , $V_{IH} = 3.3V$ , $V_{IL} = 0V$		0.8		V
V <sub>OLV</sub>	Dynamic LOW Valley Voltage (Note 5.)	$V_{CC} = 3.3V$ , $C_L = 50pF$ , $V_{IH} = 3.3V$ , $V_{IL} = 0V$		0.8		V

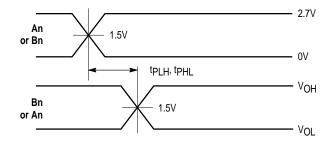
<sup>5.</sup> Number of outputs defined as "n". Measured with "n-1" outputs switching from HIGH-to-LOW or LOW-to-HIGH. The remaining output is measured in the LOW state.

#### **CAPACITIVE CHARACTERISTICS**

Symbol	Parameter	Parameter Condition		Unit
C <sub>IN</sub>	Input Capacitance	$V_{CC} = 3.3V$ , $V_I = 0V$ or $V_{CC}$	7	pF
C <sub>I/O</sub>	Input/Output Capacitance	$V_{CC} = 3.3V$ , $V_I = 0V$ or $V_{CC}$	8	pF
C <sub>PD</sub>	Power Dissipation Capacitance	10MHz, $V_{CC} = 3.3V$ , $V_I = 0V$ or $V_{CC}$	20	pF

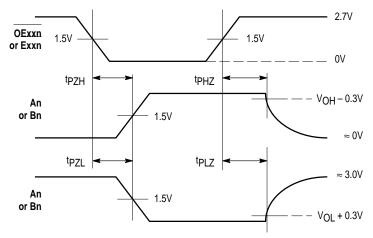
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<sup>4.</sup> Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (toshL) or LOW-to-HIGH (toslH); parameter guaranteed by design.



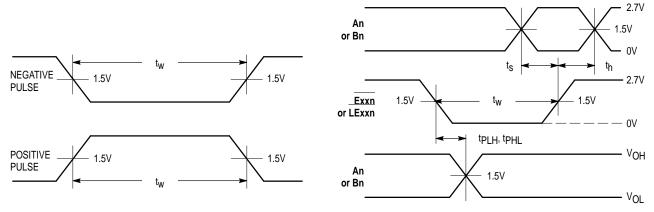
### WAVEFORM 1 - A/B to B/A PROPAGATION DELAYS

 $t_R = t_F = 2.5$ ns, 10% to 90%; f = 1MHz;  $t_W = 500$ ns



WAVEFORM 2 – OExx/Exx to A or B OUTPUT ENABLE AND DISABLE TIMES  $t_R = t_F = 2.5 ns, \, 10\% \text{ to } 90\%; \, f = 1 MHz; \, t_W = 500 ns$ 

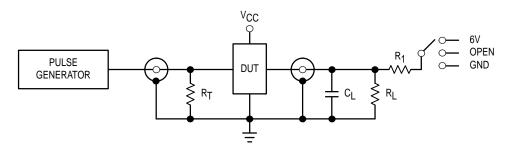
Figure 1. AC Waveforms



**WAVEFORM 3 – INPUT PULSE DEFINITION**  $t_R = t_F = 2.5$ ns, 10% to 90% of 0V to 2.7V

WAVEFORM 4 - Enable to A or B PROPAGATION DELAYS, Enable MINIMUM PULSE WIDTH, A or B to Enable SETUP AND HOLD TIMES  $t_R = t_F = 2.5 ns$ , 10% to 90%; f = 1MHz;  $t_W = 500 ns$  except when noted

Figure 2. AC Waveforms (continued)



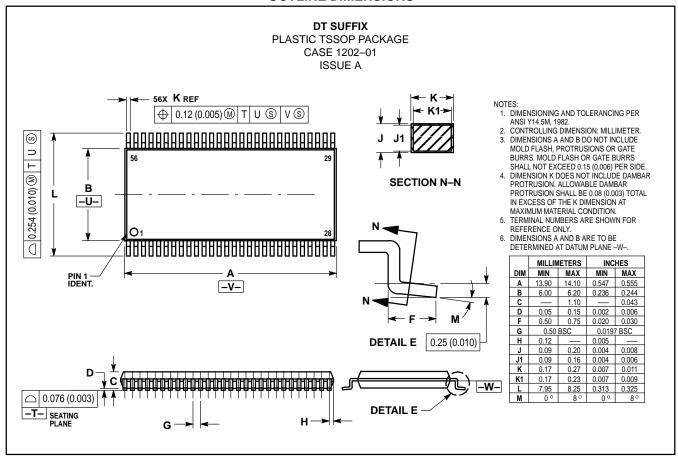
TEST	SWITCH
t <sub>PLH</sub> , t <sub>PHL</sub>	Open
tPZL, tPLZ	6V
Open Collector/Drain tpLH and tpHL	6V
<sup>t</sup> PZH <sup>, t</sup> PHZ	GND

 $C_L$  = 50pF or equivalent (Includes jig and probe capacitance)  $R_L$  =  $R_1$  = 500 $\Omega$  or equivalent  $R_T$  =  $Z_{OUT}$  of pulse generator (typically 50 $\Omega$ )

Figure 3. Test Circuit

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#### **OUTLINE DIMENSIONS**



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Mfax™: RMFAX0@email.sps.mot.com – TOUCHTONE 602–244–6609 INTERNET: http://Design=NET.com

JAPAN: Nippon Motorola Ltd.; Tatsumi–SPD–JLDC, 6F Seibu–Butsuryu–Center, 3–14–2 Tatsumi Koto–Ku, Tokyo 135, Japan. 03–81–3521–8315

ASIA/PACIFIC: Motorola Semiconductors H.K. Ltd.; 8B Tai Ping Industrial Park, 51 Ting Kok Road, Tai Po, N.T., Hong Kong. 852–26629298



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